

Search Notes**Application/Control No.**

10/803,777

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under Reexamination

ENDO ET AL.

Art Unit

1745

SEARCHED

Class	Subclass	Date	Examiner
429	121	7/17/2007	DWY
429	127	7/17/2007	DWY
429	137	7/17/2007	DWY
429	185	7/17/2007	DWY

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/17/2007	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner